

Search Notes

Application/Control No.

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Examiner

Chau Nguyen

Applicant(s)/Patent under
Reexamination

SUEHIRA, SEISHI

Art Unit

2176

SEARCHED

Class	Subclass	Date	Examiner
715	513	3/29/2006	CN
715	522	3/29/2006	CN
715	523	3/29/2006	CN
715	513	9/27/2006	CN
715	522-523	09/27/2006	CN
715	515	9/28/2006	CN
707	200	9/28/2006	CN
707	203	9/28/2006	CN
707	204	9/28/2006	CN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated Search on East Reports	3/29/2006	CN
NPL Search on IEEE Database	3/30/2006	CN
Updated Search on East Reports	9/27/2006	CN
	9/28/2006	CN